## FEATURES

Complete Monolithic 12-Bit $10 \mu$ s Sampling ADC
On-Board Sample-and-Hold Amplifier
Industry Standard Pinout
8- and 16-Bit Microprocessor Interface
AC and DC Specified and Tested
Unipolar and Bipolar Inputs
$\pm 5 \mathrm{~V}, \pm 10 \mathrm{~V}, 0 \mathrm{~V}-10 \mathrm{~V}, 0 \mathrm{~V}-20 \mathrm{~V}$ Input Ranges
Commercial, Industrial and Military Temperature Range Grades
MIL-STD-883 and SMD Compliant Versions Available

## PRODUCT DESCRIPTION

The AD 1674 is a complete, multipurpose, 12-bit analog-todigital converter, consisting of a user-transparent onboard sample-and-hold amplifier (SH A ), 10 volt reference, clock and three-state output buffers for microprocessor interface.
The AD 1674 is pin compatible with the industry standard AD 574A and AD 674A, but includes a sampling function while delivering a faster conversion rate. The on-chip SH A has a wide input bandwidth supporting 12-bit accuracy over the full N yquist bandwidth of the converter.

The AD 1674 is fully specified for ac parameters (such as $\mathrm{S} /(\mathrm{N}+\mathrm{D}$ ) ratio, THD, and IMD) and dc parameters (offset, full-scale error, etc.). With both ac and dc specifications, the AD 1674 is ideal for use in signal processing and traditional dc measurement applications.
The AD 1674 design is implemented using Analog D evices' BiM OS II process allowing high performance bipolar analog circuitry to be combined on the same die with digital CM OS logic.
Five different temperature grades are available. The AD 1674J and K grades are specified for operation over the $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ temperature range. The $A$ and $B$ grades are specified from $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$; the AD 1674T grade is specified from $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$. The J and K grades are available in both 28 -lead plastic DIP and SOIC. The A and B grade devices are available in 28-lead hermetically sealed ceramic DIP and 28-lead SOIC. The $T$ grade is available in 28 -lead hermetically sealed ceramic DIP.
*Protected by U. S. Patent Nos. 4,962,325; 4,250,445; 4,808,908; RE 30586.

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## FUNCTIONAL BLOCK DIAGRAM



## PRODUCT HIGHLIGHTS

1. Industry Standard Pinout: T he AD 1674 utilizes the pinout established by the industry standard AD 574A and AD 674A.
2. Integrated SH A: The AD 1674 has an integrated SHA which supports the full N yquist bandwidth of the converter. The SH A function is transparent to the user; no wait-states are needed for SHA acquisition.
3. DC and AC Specified: In addition to traditional dc specifications, the AD 1674 is also fully specified for frequency domain ac parameters such as total harmonic distortion, signal-to-noise ratio and input bandwidth. T hese parameters can be tested and guaranteed as a result of the onboard SHA.
4. A nalog Operation: T he precision, laser-trimmed scaling and bipolar offset resistors provide four calibrated ranges: 0 V to +10 V and 0 V to +20 V unipolar, -5 V to +5 V and -10 V to +10 V bipolar. The AD 1674 operates on +5 V and $\pm 12 \mathrm{~V}$ or $\pm 15 \mathrm{~V}$ power supplies.
5. F lexible Digital Interface: On-chip multiple-mode three-state output buffers and interface logic allow direct connection to most microprocessors.

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## AD1674- SPECIFICATIONS



| Parameter | AD 167) |  |  | AD 167K |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | Min | Typ | Max | Min | Typ | Max |  |
| RESOLUTION | 12 |  |  | 12 |  |  | Bits |
| INTEGRAL NONLINEARITY (INL) |  |  | $\pm 1$ |  |  | $\pm 1 / 2$ | LSB |
| DIFFERENTIAL NONLINEARITY (DNL) ( N o M issing Codes) | 12 |  |  | 12 |  |  | Bits |
| UNIPOLAR OFFSET ${ }^{1} @+25^{\circ} \mathrm{C}$ |  |  | $\pm 3$ |  |  | $\pm 2$ | LSB |
| BIPOLAR OFFSET ${ }^{1} @+25^{\circ} \mathrm{C}$ |  |  | $\pm 6$ |  |  | $\pm 4$ | LSB |
| FULL-SCALE ERROR ${ }^{1,2} @+25^{\circ} \mathrm{C}$ (with Fixed $50 \Omega$ Resistor from REF OUT to REF IN) |  | 0.1 | 0.25 |  | 0.1 | 0.25 | \% of FSR |
| TEMPERATURERANGE | 0 |  | +70 | 0 |  | +70 | ${ }^{\circ} \mathrm{C}$ |
| TEM PERATURE DRIFT ${ }^{3}$ <br> Unipolar Offset ${ }^{2}$ <br> Bipolar Offset ${ }^{2}$ <br> Full-Scale Error ${ }^{2}$ |  |  | $\begin{aligned} & \pm 2 \\ & \pm 2 \\ & \pm 6 \end{aligned}$ |  |  | $\begin{aligned} & \pm 1 \\ & \pm 1 \\ & \pm 3 \end{aligned}$ | $\begin{aligned} & \text { LSB } \\ & \text { LSB } \\ & \text { LSB } \end{aligned}$ |
| $\begin{aligned} & \text { POWER SUPPLY REJECTION } \\ & \mathrm{V}_{\mathrm{CC}}=15 \mathrm{~V} \pm 1.5 \mathrm{~V} \text { or } 12 \mathrm{~V} \pm 0.6 \mathrm{~V} \\ & \mathrm{~V}_{\text {LOGIC }}=5 \mathrm{~V} \pm 0.5 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{EE}}=-15 \mathrm{~V} \pm 1.5 \mathrm{~V} \text { or }-12 \mathrm{~V} \pm 0.6 \mathrm{~V} \end{aligned}$ |  |  | $\begin{aligned} & \pm 2 \\ & \pm 1 / 2 \\ & \pm 2 \\ & \hline \end{aligned}$ |  |  | $\begin{aligned} & \pm 1 \\ & \pm 1 / 2 \\ & \pm 1 \end{aligned}$ | $\begin{aligned} & \text { LSB } \\ & \text { LSB } \\ & \text { LSB } \end{aligned}$ |
| ANALOG INPUT Input Ranges Bipolar <br> U nipolar <br> Input Impedance 10 Volt Span 20 Volt Span | $\begin{aligned} & -5 \\ & -10 \\ & 0 \\ & 0 \\ & 3 \\ & 6 \end{aligned}$ | $\begin{aligned} & 5 \\ & 10 \end{aligned}$ | $\begin{aligned} & +5 \\ & +10 \\ & +10 \\ & +20 \\ & 7 \\ & 14 \end{aligned}$ | $\begin{aligned} & -5 \\ & -10 \\ & 0 \\ & 0 \\ & 3 \\ & 6 \end{aligned}$ | $\begin{aligned} & 5 \\ & 10 \end{aligned}$ | $\begin{aligned} & +5 \\ & +10 \\ & +10 \\ & +20 \\ & 7 \\ & 14 \end{aligned}$ | Volts <br> Volts <br> Volts <br> Volts <br> k $\Omega$ <br> $\mathrm{k} \Omega$ |
| POWER SUPPLIES <br> O perating Voltages <br> $V_{\text {Logic }}$ <br> $V_{\text {cc }}$ <br> $V_{E E}$ <br> Operating Current I logic <br> Icc <br> $I_{\text {EE }}$ | $\begin{aligned} & +4.5 \\ & +11.4 \\ & -16.5 \end{aligned}$ | 5 <br> 10 <br> 14 | $\begin{aligned} & +5.5 \\ & +16.5 \\ & -11.4 \\ & 8 \\ & 14 \\ & 18 \end{aligned}$ | $\begin{aligned} & +4.5 \\ & +11.4 \\ & -16.5 \end{aligned}$ | 5 <br> 10 <br> 14 | $\begin{aligned} & +5.5 \\ & +16.5 \\ & -11.4 \\ & 8 \\ & 14 \\ & 18 \end{aligned}$ | Volts <br> Volts <br> Volts <br> mA <br> mA <br> mA |
| POWER DISSIPATION |  | 385 | 575 |  | 385 | 575 | mW |
| internal reference voltage Output Current (A vailable for External Loads) ${ }^{4}$ (External Load Should $N$ ot Change D uring C onversion | 9.9 | 10.0 | $\begin{aligned} & 10.1 \\ & 2.0 \end{aligned}$ | 9.9 | 10.0 | $\begin{aligned} & 10.1 \\ & 2.0 \end{aligned}$ | Volts mA |

## NOTES

${ }^{1}$ Adjustable to zero.
${ }^{2}$ Includes internal voltage reference error.
${ }^{3} \mathrm{M}$ aximum change from $25^{\circ} \mathrm{C}$ value to the value at $\mathrm{T}_{\text {MIN }}$ or $\mathrm{T}_{\text {MAX }}$.
${ }^{4}$ R eference should be buffered for $\pm 12 \mathrm{~V}$ operation.
All min and max specifications are guaranteed.
Specifications subject to change without notice.


## AD1674- SPECIFICATIONS

AC SPECIFICATIONS ${ }^{\left(\mathrm{T}_{\text {MIN }} \text { to }\right.} \mathrm{T}_{\text {Max, }}$, with $\mathrm{V}_{\mathrm{CC}}=+15 \mathrm{~V} \pm 10 \%$ or $+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\text {LOGIC }}=+5 \mathrm{~V} \pm 10 \%, \mathrm{~V}_{\text {EE }}=-15 \mathrm{~V} \pm 10 \%$ or
AC SPECIFICAIIONS - $12 \mathrm{~V} \pm 5 \%, \mathrm{f}_{\text {SAMPLE }}=100 \mathrm{kSPS}, \mathrm{f}_{\mathrm{IN}}=10 \mathrm{kHz}$, stand-alone mode unless otherwise noted) ${ }^{1}$

| Parameter | AD1674/A |  |  | AD 1674/B/T |  |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | Min | Typ | Max | Min | Typ | Max |  |
| Signal to N oise and Distortion (S/N+D) Ratio ${ }^{\text {2, }} 3$ | 69 | 70 |  | 70 | 71 |  | dB |
| T otal H armonic Distortion (THD ) ${ }^{4}$ |  | -90 | $\begin{aligned} & -82 \\ & 0.008 \end{aligned}$ |  | -90 | $\begin{aligned} & -82 \\ & 0.008 \end{aligned}$ | $\begin{aligned} & \mathrm{dB} \\ & \% \end{aligned}$ |
| Peak Spurious or Peak H armonic C omponent |  | -92 | -82 |  | -92 | -82 | dB |
| Full Power Bandwidth <br> Full Linear Bandwidth |  | $\begin{aligned} & 1 \\ & 500 \end{aligned}$ |  | $\begin{aligned} & 1 \\ & 500 \end{aligned}$ |  |  | $\mathrm{MHz}$ $\mathrm{kHz}$ |
| Intermodulation Distortion (IM D ) ${ }^{5}$ <br> Second Order Products <br> Third Order Products |  | $\begin{aligned} & -90 \\ & -90 \end{aligned}$ | $\begin{aligned} & -80 \\ & -80 \end{aligned}$ |  | $\begin{aligned} & -90 \\ & -90 \end{aligned}$ | $\begin{aligned} & -80 \\ & -80 \end{aligned}$ | $\begin{aligned} & \mathrm{dB} \\ & \mathrm{~dB} \end{aligned}$ |
| SHA (Specifications are Included in Overall T iming Specifications) <br> A perture D elay <br> A perture Jitter <br> Acquisition Time |  | $\begin{aligned} & 50 \\ & 250 \\ & 1 \end{aligned}$ |  |  | $\begin{aligned} & 50 \\ & 250 \\ & 1 \end{aligned}$ |  | $\begin{aligned} & \mathrm{ns} \\ & \mathrm{ps} \\ & \mu \mathrm{~s} \end{aligned}$ |

DIGITAL SPECIFICATIONS (for all grades $\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {max }}$, with $\mathrm{V}_{\mathrm{cc}}=+15 \mathrm{~V} \pm 10 \%$ or $+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{LoGG}}=+5 \mathrm{~V} \pm 10 \%$,
D|G|TAL SPECIFICATIONS $V_{E E}=-15 \mathrm{~V} \pm 10 \%$ or $-12 \mathrm{~V} \pm 5 \%$ )

| Parameter | Test Conditions | Min | Max | Units |
| :---: | :---: | :---: | :---: | :---: |
| LOGIC INPUTS |  |  |  |  |
| $V_{\text {IH }} \quad$ High Level Input Voltage |  | +2.0 | $\mathrm{V}_{\text {LOGIC }}+0.5 \mathrm{~V}$ | V |
| $\mathrm{V}_{\text {IL }} \quad$ Low L evel Input Voltage |  | -0.5 | +0.8 | V |
| $\mathrm{I}_{\mathrm{IH}} \quad$ High Level Input C urrent ( $\left.\mathrm{V}_{\text {IN }}=5 \mathrm{~V}\right)$ | $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\text {LOGIC }}$ | -10 | +10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{IL}} \quad$ Low Level Input Current ( $\left.\mathrm{V}_{\text {IN }}=0 \mathrm{~V}\right)$ | $\mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ | -10 | +10 | $\mu \mathrm{A}$ |
| $\mathrm{C}_{\text {IN }} \quad$ Input Capacitance |  |  | 10 | pF |
| LOGIC OUTPUTS |  |  |  |  |
| $\mathrm{V}_{\text {OH }} \quad$ High L evel Output Voltage | $\mathrm{I}_{\mathrm{OH}}=0.5 \mathrm{~mA}$ | +2.4 |  | V |
| $V_{0 L}$ Low Level Output Voltage | $\mathrm{I}_{\text {OL }}=1.6 \mathrm{~mA}$ |  | +0.4 | V |
| Ioz High-Z Leakage Current | $\mathrm{V}_{\text {IN }}=0$ to $\mathrm{V}_{\text {LOGIC }}$ | -10 | +10 | $\mu \mathrm{A}$ |
| $\mathrm{C}_{\text {oz }} \quad \mathrm{H}$ igh-Z Output Capacitance |  |  | 10 | pF |

## NOTES

${ }^{1} \mathrm{f}_{\mathrm{IN}}$ amplitude $=-0.5 \mathrm{~dB}(9.44 \mathrm{~V} p-\mathrm{p}) 10 \mathrm{~V}$ bipolar mode unless otherwise noted. All measurements referred to $-0 \mathrm{~dB}(9.997 \mathrm{~V} p-\mathrm{p})$ input signal unless
otherwise noted.
${ }^{2}$ Specified at worst case temperatures and supplies after one minute warm-up.
${ }^{3}$ See Figures 12 and 13 for other input frequencies and amplitudes.
${ }^{4}$ See Figure 11.
${ }^{5} \mathrm{fa}=9.08 \mathrm{kHz}$, $\mathrm{fb}=9.58 \mathrm{kHz}$ with $\mathrm{f}_{\text {SAM PLE }}=100 \mathrm{kHz}$. See Definition of Specifications section and Figure 15.
All min and max specifications are guaranteed.
Specifications subject to change without notice.
(for all grades $\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAX }}$ with $\mathrm{V}_{\mathrm{CC}}=+15 \mathrm{~V} \pm 10 \%$ or $+12 \mathrm{~V} \pm 5 \%$,
$V_{\text {LOGIC }}=+5 \mathrm{~V} \pm 10 \%, \mathrm{~V}_{\text {EE }}=-15 \mathrm{~V} \pm 10 \%$ or $-12 \mathrm{~V} \pm 5 \% ; \mathrm{V}_{\mathrm{IL}}=0.4 \mathrm{~V}$,
SW|TCH|NG SPECIF|CAT|ONS $V_{I H}=2.4 \mathrm{~V}$ unless otherwise noted)

CONVERTER START TIMING (Figure 1)

| Parameter | Symbol | J, K, A, B, Grades Min Typ Max |  | T Grade Min Typ Max |  |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Conversion Time |  |  |  |  |  |  |  |
| 8-Bit Cycle | $\mathrm{t}_{\mathrm{c}}$ | 7 | 8 |  |  | 8 | $\mu \mathrm{S}$ |
| 12-Bit Cycle | $\mathrm{t}_{\mathrm{c}}$ |  | 10 |  |  | 10 | $\mu \mathrm{S}$ |
| ST S D elay from CE | $\mathrm{t}_{\text {DSC }}$ |  | 200 |  |  | 225 | ns |
| CE Pulse Width | $\mathrm{thec}^{\text {c }}$ | 50 |  | 50 |  |  | ns |
| $\overline{\mathrm{CS}}$ to CE Setup | $\mathrm{t}_{\text {SSC }}$ | 50 |  | 50 |  |  | ns |
| $\overline{\mathrm{CS}}$ L ow During CE High | $\mathrm{t}_{\mathrm{HSC}}$ | 50 |  | 50 |  |  | ns |
| R/C ${ }^{\text {c }}$ to CE Setup | $t_{\text {SRC }}$ | 50 |  | 50 |  |  | ns |
| R/C L ow During CE High | $\mathrm{t}_{\text {HRC }}$ | 50 |  | 50 |  |  | ns |
| $\mathrm{A}_{0}$ to CE Setup | $\mathrm{t}_{\text {SAC }}$ | 0 |  | 0 |  |  | ns |
| $A_{0}$ Valid During CE High | $\mathrm{thaC}^{\text {a }}$ | 50 |  | 50 |  |  | ns |

READ TIMING-FULL CONTROL MODE (Figure 2)

| Parameter | Symbol | J, K, A, B, Grades |  |  | T Grade |  |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Typ | Max |  |
| Access Time | $\mathrm{t}_{\mathrm{DD}}{ }^{1}$ |  | 75 | 150 |  |  | 150 | ns |
| D ata Valid After CE Low | $\mathrm{thD}^{\text {d }}$ | $25^{2}$ |  |  | $25^{2}$ |  |  | ns |
|  |  | $20^{3}$ |  |  | $15^{4}$ |  |  | ns |
| Output Float D elay | $t_{H L}{ }^{5}$ |  |  | 150 |  |  | 150 | ns |
| $\overline{\mathrm{CS}}$ to CE Setup | $\mathrm{t}_{\text {SSR }}$ | 50 |  |  | 50 |  |  | ns |
| R/C to CE Setup | $\mathrm{t}_{\text {SRR }}$ | 0 |  |  | 0 |  |  | ns |
| $\mathrm{A}_{0}$ to CE Setup | $\mathrm{t}_{\text {SAR }}$ | 50 |  |  | 50 |  |  | ns |
| $\overline{\mathrm{CS}}$ Valid After CE Low | $\mathrm{t}_{\text {HSR }}$ | 0 |  |  | 0 |  |  | ns |
| R/C High After CE Low | $\mathrm{t}_{\text {HRR }}$ | 0 |  |  | 0 |  |  | ns |
| $\mathrm{A}_{0}$ Valid After CE Low | $t_{\text {HAR }}$ | 50 |  |  | 50 |  |  | ns |

NOTES
${ }^{1} t_{D D}$ is measured with the load circuit of Figure 3 and is defined as the time
required for an output to cross 0.4 V or 2.4 V .
${ }^{2} 0^{\circ} \mathrm{C}$ to $\mathrm{T}_{\text {max }}$.
${ }^{3}$ At $-40^{\circ} \mathrm{C}$.
${ }^{4} \mathrm{At}-55^{\circ} \mathrm{C}$.
${ }^{5} t_{H L}$ is defined as the time required for the data lines to change 0.5 V when loaded with the circuit of Figure 3.
All min and max specifications are guaranteed.
Specifications subject to change without notice.

| Test | $\mathbf{V}_{\mathbf{C P}}$ | Cout |
| :--- | :--- | :--- |
| Access T ime High Z to L ogic L ow | 5 V | 100 pF |
| Float Time Logic H igh to High Z | 0 V | 10 pF |
| Access Time High Z to Logic High | 0 V | 100 pF |
| Float Time Logic L ow to High Z | 5 V | 10 pF |



Figure 1. Converter Start Timing


Figure 2. Read Timing


Figure 3. Load Circuit for Bus Timing Specifications

TIMING-STAND-ALONE MODE (Figures 4a and 4b)

| Parameter | Symbol | J, K, A, B Grades |  |  | T Grade |  |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Typ | Max |  |
| D ata Access T ime | $t_{\text {DDR }}$ |  |  | 150 |  |  | 150 | ns |
| Low R/C Pulse Width | $\mathrm{t}_{\mathrm{HRL}}$ | 50 |  |  | 50 |  |  | ns |
| STS D elay from R/C | $\mathrm{t}_{\mathrm{DS}}$ |  |  | 200 |  |  | 225 | ns |
| D ata Valid After R/C L ow | $\mathrm{t}_{\mathrm{HDR}}$ | 25 |  |  | 25 |  |  | ns |
| STS D elay After D ata Valid | $\mathrm{t}_{\mathrm{HS}}$ | 0.6 | 0.8 | 1.2 | 0.6 | 0.8 | 1.2 | $\mu \mathrm{s}$ |
| $\underline{\text { High R/C Pulse Width }}$ | $\mathrm{t}_{\mathrm{HRH}}$ | 150 |  |  | 150 |  |  | ns |

## NOTE

All min and max specifications are guaranteed.
Specifications subject to change without notice.


Figure 4a. Stand-Alone Mode Timing Low Pulse for $R \bar{C}$

## ABSOLUTE MAXIMUM RATINGS*

$V_{C C}$ to Digital Common ........................ . 0 to +16.5 V
$\mathrm{V}_{\mathrm{EE}}$ to Digital Common . . . . . . . . . . . . . . . . . . . . . . 0 to -16.5 V
$V_{\text {LoGic }}$ to Digital Common ........................ . 0 V to +7 V
Analog Common to D igital Common . . . . . . . . . . . . . . $\pm 1$ V
Digital Inputs to Digital Common ... -0.5 V to $\mathrm{V}_{\text {LOGIC }}+0.5 \mathrm{~V}$
A nalog Inputs to Analog Common ............... $\mathrm{V}_{\mathrm{EE}}$ to $\mathrm{V}_{\mathrm{CC}}$
$20 \mathrm{~V}_{\text {IN }}$ to Analog Common ...................... . $\mathrm{V}_{\text {EE }}$ to +24 V
REF OUT . . . . . . . . . . . . . . . . Indefinite Short to Common


Figure 4b. Stand-Alone Mode Timing High Pulse for R/C . . . . . . . . . . . . . . . . . . . . . . . . . . . M omentary Short to $\mathrm{V}_{\mathrm{cc}}$
Junction Temperature . . . . . . . . . . . . . . . . . . . . . . . . . $+175^{\circ} \mathrm{C}$
Power Dissipation . . . . . . . . . . . . . . . . . . . . . . . . . . . . 825 mW
Lead Temperature, Soldering ( 10 sec ) . . . . . . . $+300^{\circ} \mathrm{C}, 10 \mathrm{sec}$
Storage Temperature . . . . . . . . . . . . . . . . . . . $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
*Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulateon the human body and test equipment and can discharge without detection. Although the AD 1674 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.


ORDERING GUIDE

| Model ${ }^{1}$ | Temperature Range | INL <br> ( $T_{\text {MIN }}$ to $T_{\text {MAX }}$ ) | $\begin{aligned} & S /(N+D) \\ & \left(T_{\text {MIN }} \text { to } T_{\text {MAX }}\right) \end{aligned}$ | Package Description | Package Option ${ }^{2}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| AD 1674JN | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | $\pm 1$ LSB | 69 dB | Plastic DIP | N-28 |
| AD 1674K N | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | $\pm 1 / 2 \mathrm{LSB}$ | 70 dB | Plastic DIP | N-28 |
| AD 1674JR | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | $\pm 1$ LSB | 69 dB | Plastic SOIC | R-28 |
| AD 1674K R | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | $\pm 1 / 2$ LSB | 70 dB | Plastic SOIC | R-28 |
| AD 1674AR | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $\pm 1 \mathrm{LSB}$ | 69 dB | Plastic SOIC | R-28 |
| AD 1674BR | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $\pm 1 / 2$ LSB | 70 dB | Plastic SOIC | R-28 |
| AD 1674AD | $-40^{\circ} \mathrm{C}$ to $+85{ }^{\circ} \mathrm{C}$ | $\pm 1 \mathrm{LSB}$ | 69 dB | Ceramic DIP | D-28 |
| AD 1674BD | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $\pm 1 / 2$ LSB | 70 dB | Ceramic DIP | D-28 |
| AD 1674T D | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | $\pm 1$ LSB | 70 dB | Ceramic DIP | D-28 |

[^1]
## PIN DESCRIPTION

| Symbol | Pin No. | Type | Name and Function |
| :---: | :---: | :---: | :---: |
| AGND | 9 | P | Analog Ground (Common). |
| $\mathrm{A}_{0}$ | 4 | DI | Byte Address/Short Cycle. If a conversion is started with $\mathrm{A}_{0}$ Active LOW, a full 12 -bit conversion cycle is initiated. If $\mathrm{A}_{0}$ is Active HIGH during a convert start, a shorter 8 -bit conversion cycle results. During Read $(\mathrm{R} / \overline{\mathrm{C}}=1)$ with $12 / \overline{8} \mathrm{LOW}, \mathrm{A}_{0}=$ LOW enables the 8 most significant bits (DB4-DB11), and $A_{0}=$ HIGH enables DB3-DB0 and sets DB7-DB4 $=0$. |
| BIP OFF | 12 | AI | Bipolar Offset. Connect through a $50 \Omega$ resistor to REF OUT for bipolar operation or to Analog Common for unipolar operation. |
| CE | 6 | DI | Chip Enable. Chip Enable is Active HIGH and is used to initiate a convert or read operation. |
| $\overline{\mathrm{CS}}$ | 3 | DI | Chip Select. Chip Select is Active LOW . |
| DB11-DB8 | 27-24 | DO | Data Bits 11 through 8 . In the 12 -bit format (see $12 / \overline{8}$ and $A_{0}$ pins), these pins provide the upper 4 bits of data. In the 8 -bit format, they provide the upper 4 bits when $A_{0}$ is LOW and are disabled when $\mathrm{A}_{0}$ is HIGH. |
| DB7-DB4 | 23-20 | D 0 | D ata Bits 7 through 4. In the 12-bit format these pins provide the middle 4 bits of data. In the 8 -bit format they provide the middle 4 bits when Ao is LOW and all zeroes when $\mathrm{A}_{0}$ is HIGH . |
| DB3-DB0 | 19-16 | DO | D ata Bits 3 through 0 . In the 12-bit format these pins provide the lower 4 bits of data. In the 8 -bit format these pins provide the lower 4 bits of data when $A_{0}$ is HIGH , they are disabled when $A_{0}$ is LOW. |
| DGND | 15 | P | D igital Ground (Common). |
| REF OUT | 8 | AO | +10 V Reference Output. |
| R/C | 5 | DI | Read/C onvert. In the full control mode R/C is Active HIGH for a read operation and Active LOW for a convert operation. In the stand-alone mode, the falling edge of $R / \bar{C}$ initiates a conversion. |
| REF IN | 10 | AI | Reference Input is connected through a $50 \Omega$ resistor to +10 V Reference for normal operation. |
| STS | 28 | DO | Status is Active HIGH when a conversion is in progress and goes LOW when the conversion is completed. |
| $\mathrm{V}_{\text {CC }}$ | 7 | P | +12 V/+15 V Analog Supply. |
| $V_{\text {EE }}$ | 11 | P | -12 V/-15 V Analog Supply. |
| $V_{\text {LOGIC }}$ | 1 | P | +5 V Logic Supply. |
| $10 \mathrm{~V}_{\text {IN }}$ | 13 | AI | 10 V Span Input, 0 V to +10 V unipolar mode or -5 V to +5 V bipolar mode. When using the AD 1674 in the 20 V Span $10 \mathrm{~V}_{\text {IN }}$ should not be connected. |
| $20 \mathrm{~V}_{\text {IN }}$ | 14 | AI | 20 V Span Input, 0 V to +20 V unipolar mode or -10 V to +10 V bipolar mode. When using the AD 1674 in the 10 V Span $20 \mathrm{~V}_{\text {IN }}$ should not be connected. |
| 12/8 | 2 | DI | T he $12 / \overline{8}$ pin determines whether the digital output data is to be organized as two 8 -bit words ( $12 / \overline{8} \mathrm{LOW}$ ) or a single 12 -bit word ( $12 / \overline{8}$ HIG H). |

TYPE: $\mathrm{AI}=$ Analog Input

AO = Analog Output
DI = Digital Input
DO = Digital Output
$\mathrm{P}=$ Power

FUNCTIONAL BLOCK DIAGRAM


PIN CONFIGURATION


## AD1674

## DEFINITION OF SPECIFICATIONS

## INTEGRAL NONLINEARITY (INL)

The ideal transfer function for an ADC is a straight line drawn between "zero" and "full scale." The point used as "zero" occurs $1 / 2$ LSB before the first code transition. "F ull scale" is defined as a level $11 / 2$ LSB beyond the last code transition. Integral nonlinearity is the worst-case deviation of a code from the straight line. The deviation of each code is measured from the middle of that code.

## DIFFERENTIAL NONLINEARITY (DNL)

A specification which guarantees no missing codes requires that every code combination appear in a monotonic increasing sequence as the analog input level is increased. Thus every code must have a finite width. The AD 1674 guarantees no missing codes to 12-bit resolution; all 4096 codes are present over the entire operating range.

## UNIPOLAR OFFSET

The first transition should occur at a level 1/2 LSB above analog common. Unipolar offset is defined as the deviation of the actual transition from that point at $25^{\circ} \mathrm{C}$. This offset can be adjusted as shown in Figure 11.

## BIPOLAR OFFSET

In the bipolar mode the major carry transition (0111 11111111 to 100000000000 ) should occur for an analog value $1 / 2$ LSB below analog common. The bipolar offset error specifies the deviation of the actual transition from that point at $25^{\circ} \mathrm{C}$. This offset can be adjusted as shown in Figure 12.

## FULL-SCALE ERROR

The last transition (from 111111111110 to 11111111 1111) should occur for an analog value $11 / 2$ LSB below the nominal full scale ( 9.9963 volts for 10 volts full scale). T he full-scale error is the deviation of the actual level of the last transition from the ideal level at $25^{\circ} \mathrm{C}$. The full-scale error can be adjusted to zero as shown in Figures 11 and 12.

## TEMPERATURE DRIFT

The temperature drifts for full-scale error, unipolar offset and bipolar offset specify the maximum change from the initial $\left(25^{\circ} \mathrm{C}\right)$ value to the value at $\mathrm{T}_{\text {MIN }}$ or $\mathrm{T}_{\text {MAX }}$.

## POWER SUPPLY REJECTION

The effect of power supply error on the performance of the device will be a small change in full scale. The specifications show the maximum full-scale change from the initial value with the supplies at various limits.

## FREQUENCY-DOMAIN TESTING

The AD 1674 is tested dynamically using a sine wave input and a 2048 point F ast F ourier T ransform (FFT) to analyze the resulting output. C oherent sampling is used, wherein the ADC sampling frequency and the analog input frequency are related to each other by a ratio of integers. T his ensures that an integral multiple of input cycles is captured, allowing direct FFT processing without windowing or digital filtering which could mask some of the dynamic characteristics of the device. In addition, the frequencies are chosen to he "relatively prime" (no common factors) to maximize the number of different ADC codes that
are present in a sample sequence. The result, called Prime C oherent Sampling, is a highly accurate and repeatable measure of the actual frequency-domain response of the converter.

## NYQUIST FREQUENCY

An implication of the $N$ yquist sampling theorem, the " $N$ yquist F requency" of a converter is that input frequency which is onehalf the sampling frequency of the converter.

## SIGNAL-TO-NOISE AND DISTORTION (S/N+D) RATIO

 $S /(N+D)$ is the ratio of the rms value of the measured input signal to the rms sum of all other spectral components below the $N$ yquist frequency, including harmonics but excluding dc. The value for $S /(N+D)$ is expressed in decibels.
## TOTAL HARMONIC DISTORTION (THD)

THD is the ratio of the rms sum of the first six harmonic components to the rms value of a full-scale input signal and is expressed as a percentage or in decibels. For input signals or harmonics that are above the $N$ yquist frequency, the aliased component is used.

## INTERMODULATION DISTORTION (IMD)

With inputs consisting of sine waves at two frequencies, fa and fb, any device with nonlinearities will create distortion products, of order ( $m+n$ ), at sum and difference frequencies of $m f a \pm n f b$, where $\mathrm{m}, \mathrm{n}=0,1,2,3 \ldots$ Intermodulation terms are those for which m or n is not equal to zero. For example, the second order terms are ( $\mathrm{fa}+\mathrm{fb}$ ) and ( $\mathrm{fa}-\mathrm{fb}$ ) and the third order terms are $(2 f a+f b),(2 f a-f b),(f a+2 f b)$ and (fa $-2 f b)$. The IM D products are expressed as the decibel ratio of the rms sum of the measured input signals to the rms sum of the distortion terms. T he two signals are of equal amplitude and the peak value of their sums is -0.5 dB from full scale. The IM D products are normalized to a 0 dB input signal.

## FULL-POWER BANDWIDTH

The full-power bandwidth is that input frequency at which the amplitude of the reconstructed fundamental is reduced by 3 dB for a full-scale input.

## FULL-LINEAR BANDWIDTH

The full-linear bandwidth is the input frequency at which the slew rate limit of the sample-hold-amplifier (SHA) is reached. At this point, the amplitude of the reconstructed fundamental has degraded by less than -0.1 dB . Beyond this frequency, distortion of the sampled input signal increases significantly.

## APERTURE DELAY

A perture delay is a measure of the SH A's performance and is measured from the falling edge of Read/C onvert ( $R / \overline{\mathrm{C}}$ ) to when the input signal is held for conversion.

## APERTURE JITTER

A perture jitter is the variation in aperture delay for successive samples and is manifested as noise on the input to the A/D.


Figure 5. Harmonic Distortion vs. Input Frequency


Figure 6. $S /(N+D)$ vs. Input Frequency and Amplitude


Figure 7. $S /(N+D)$ vs. Input Amplitude


Figure 8. Nonaveraged 2048 Point FFT at $100 \mathrm{kSPS}, f_{I N}=25.049 \mathrm{kHz}$

## GENERAL CIRCUIT OPERATION

The AD 1674 is a complete 12 -bit, $10 \mu$ sampling analog-todigital converter. A block diagram of the AD 1674 is shown on page 7.
When the control section is commanded to initiate a conversion (as described later), it places the sample-and-hold amplifier (SHA) in the hold mode, enables the clock, and resets the successive approximation register (SAR). Once a conversion cycle has begun, it cannot be stopped or restarted and data is not available from the output buffers. The SAR, timed by the internal clock, will sequence through the conversion cycle and return an end-of-convert flag to the control section when the conversion has been completed. The control section will then disable the clock, switch the SHA to sample mode, and delay the ST S LOW going edge to allow for acquisition to 12-bit accuracy. The control section will allow data read functions by external command anytime during the SH A acquisition interval.
D uring the conversion cycle, the internal 12-bit, 1 mA full-scale current output DAC is sequenced by the SAR from the most significant bit (M SB) to the least significant bit (LSB) to provide an output that accurately balances the current through the $5 \mathrm{k} \Omega$ resistor from the input signal voltage held by the SHA. The SH A's input scaling resistors divide the input voltage by 2 for the 10 V input span and by 4 V for the 20 V input span, maintaining a 1 mA full-scale output current through the $5 \mathrm{k} \Omega$ resistor for both ranges. The comparator determines whether the addition of each successively weighted bit current causes the


Figure 9. IMD Plot for $f_{I N}=9.08 \mathrm{kHz}$ (fa), 9.58 kHz (fb)

DAC current sum to be greater than or less than the input current. If the sum is less, the bit is left on; if more, the bit is turned off. After testing all the bits, the SAR contains a 12-bit binary code which accurately represents the input signal to within $\pm 1 / 2$ LSB.

## CONTROL LOGIC

The AD 1674 may be operated in one of two modes, the fullcontrol mode and the stand-alone mode. The full-control mode utilizes all the AD 1674 control signals and is useful in systems that address decode multiple devices on a single data bus. The stand-alone mode is useful in systems with dedicated input ports available and thus not requiring full bus interface capability. Table I is a truth table for the AD 1674, and Figure 10 illustrates the internal logic circuitry.

Table I. AD1674A Truth Table

| $\mathbf{C E}$ | $\overline{\mathbf{C S}}$ | $\mathbf{R} / \overline{\mathbf{C}}$ | $\mathbf{1 2} / \overline{\mathbf{8}}$ | $\mathbf{A}_{\mathbf{0}}$ | Operation |
| :--- | :--- | :--- | :--- | :--- | :--- |
| 0 | X | X | X | X | N one |
| X | 1 | X | X | X | N one |
| 1 | 0 | 0 | $X$ | 0 | Initiate 12-Bit C onversion |
| 1 | 0 | 0 | X | 1 | Initiate 8-Bit C onversion |
| 1 | 0 | 1 | 1 | X | Enable 12-Bit Parallel Output |
| 1 | 0 | 1 | 0 | 0 | Enable 8 M ost Significant Bits |
| 1 | 0 | 1 | 0 | 1 | Enable 4 LSB S +4 Trailing Zeroes |



Figure 10. Equivalent Internal Logic Circuitry

## FULL-CONTROL MODE

Chip Enable (CE), Chip Select ( $\overline{\mathrm{CS}}$ ) and Read/ Convert ( $\mathrm{R} / \overline{\mathrm{C}}$ ) are used to control Convert or Read modes of operation. Either CE or $\overline{\mathrm{CS}}$ may be used to initiate a conversion. The state of $\mathrm{R} / \overline{\mathrm{C}}$ when $C E$ and $\overline{\mathrm{CS}}$ are both asserted determines whether a data Read ( $R / \bar{C}=1$ ) or a Convert ( $R / \bar{C}=0$ ) is in progress. $R / \bar{C}$ should be LOW before both CE and $\overline{\mathrm{CS}}$ are asserted; if R/C is HIGH, a Read operation will momentarily occur, possibly resulting in system bus contention.

## STAND-ALONE MODE

The AD 1674 can be used in a "stand-alone" mode, which is useful in systems with dedicated input ports available and thus not requiring full bus interface capability. Stand-alone mode applications are generally able to issue conversion start commands more precisely than full-control mode. This improves ac performance by reducing the amount of control-induced aperture jitter.
In stand-alone mode, the control interface for the AD 1674 and AD 674A are identical. CE and $12 / \overline{8}$ are wired HIGH, $\overline{\mathrm{CS}}$ and $A_{0}$ are wired LOW, and conversion is controlled by R/C. The three-state buffers are enabled when R/C is HIGH and a conversion starts when R/C goes L OW. This gives rise to two possible control signals-a high pulse or a low pulse. Operation with a low pulse is shown in Figure 4a. In this case, the outputs are forced into the high impedance state in response to the falling edge of $\mathrm{R} / \mathrm{C}$ and return to valid logic levels after the conversion cycle is completed. The ST S line goes H IG H 200 ns after $\mathrm{R} / \overline{\mathrm{C}}$ goes LOW and returns low $1 \mu \mathrm{~s}$ after data is valid.
If conversion is initiated by a high pulse as shown in Figure 4b, the data lines are enabled during the time when $\mathrm{R} / \overline{\mathrm{C}}$ is HIGH. The falling edge of $R / \bar{C}$ starts the next conversion and the data lines return to three-state (and remain three-state) until the next high pulse of $R / \bar{C}$.

## CONVERSION TIMING

Once a conversion is started, the ST S line goes HIGH. Convert start commands will be ignored until the conversion cycle is complete. The output data buffers will be enabled a minimum of $0.6 \mu$ s prior to ST S going LOW. The STS line will return LOW at the end of the conversion cycle.

The register control inputs, $\mathrm{A}_{0}$ and $12 / \overline{8}$, control conversion length and data format. If a conversion is started with $\mathrm{A}_{0} \mathrm{LOW}$, a full 12 -bit conversion cycle is initiated. If $\mathrm{A}_{0}$ is HIGH during a convert start, a shorter 8-bit conversion cycle results.
D uring data read operations, $A_{0}$ determines whether the threestate buffers containing the 8 M SBs of the conversion result ( $\mathrm{A}_{0}$ $=0)$ or the $4 \mathrm{LSBs}\left(\mathrm{A}_{0}=1\right)$ are enabled. The $12 / \overline{8}$ pin determines whether the output data is to be organized as two 8-bit words ( $12 / \overline{8}$ tied LOW) or a single 12-bit word ( $12 / \overline{8}$ tied HIGH ). In the 8-bit mode, the byte addressed when $A_{0}$ is high contains the 4 LSBs from the conversion followed by four trailing zeroes. T his organization allows the data lines to be overlapped for direct interface to 8-bit buses without the need for external three-state buffers.

## INPUT CONNECTIONS AND CALIBRATION

The $10 \mathrm{~V} p-p$ and $20 \mathrm{~V} p-\mathrm{p}$ full-scale input ranges of the AD 1674 accept the majority of signal voltages without the need for external voltage divider networks which could deteriorate the accuracy of the ADC.
The AD 1674 is factory trimmed to minimize offset, linearity, and full-scale errors. In many applications, no calibration trimming will be required and the AD 1674 will exhibit the accuracy limits listed in the specification tables.
In some applications, offset and full-scale errors need to be trimmed out completely. The following sections describe the correct procedure for these various situations.

## UNIPOLAR RANGE INPUTS

Figure 11 illustrates the external connections for the AD 1674 in unipolar-input mode. The first output-code transition (from 000000000000 to 00000000 0001) should nominally occur for an input level of $+1 / 2$ LSB ( 1.22 mV above ground for a 10 V range; 2.44 mV for a 20 V range). To trim unipolar offset to this nominal value, apply a $+1 / 2$ LSB signal between $P$ in 13 and ground ( 10 V range) or Pin 14 and ground ( 20 V range) and adjust R1 until the first transition is located. If the offset trim is not required, Pin 12 can be connected directly to Pin 9; the two resistors and trimmer for Pin 12 are then not needed.


Figure 11. Unipolar Input Connections with Gain and Offset Trims

The full-scale trim is done by applying a signal 1 1/2 LSB below the nominal full scale ( 9.9963 V for a 10 V range) and adjusting R2 until the last transition is located (1111 11111110 to 1111 1111 1111). If full-scale adjustment is not required, R2 should be replaced with a fixed $50 \Omega \pm 1 \%$ metal film resistor. If REF OUT is connected directly to REF IN, the additional full-scale error will be approximately $1 \%$.

## BIPOLAR RANGE INPUTS

The connections for the bipolar-input mode are shown in Figure 12. Either or both of the trimming potentiometers can be replaced with $50 \Omega \pm 1 \%$ fixed resistors if the specified AD 1674 accuracy limits are sufficient for the application. If the pins are shorted together, the additional offset and gain errors will be approximately $1 \%$.
To trim bipolar offset to its nominal value, apply a signal $1 / 2$ LSB below midrange ( -1.22 mV for $\mathrm{a} \pm 5 \mathrm{~V}$ range) and adjust R1 until the major carry transition is located ( 011111111111 to 100000000000 ). T o trim the full-scale error, apply a signal $11 / 2 \mathrm{LSB}$ below full scale ( +4.9963 V for $\mathrm{a} \pm 5 \mathrm{~V}$ range) and adjust R 2 to give the last positive transition (1111 11111110 to 11111111 1111). These trims are interactive so several iterations may be necessary for convergence.
A single-pass calibration can be done by substituting a negative full-scale trim for the bipolar offset trim (error at midscale), using the same circuit. First, apply a signal $1 / 2$ LSB above minus full scale ( -4.9988 V for $\mathrm{a} \pm 5 \mathrm{~V}$ range) and adjust R 1 until the minus full-scale transition is located ( 000000000001 to 0000 00000000 ). Then perform the gain error trim as outlined above.


Figure 12. Bipolar Input Connections with Gain and Offset Trims

## REFERENCE DECOUPLING

It is recommended that a $10 \mu \mathrm{~F}$ tantalum capacitor be connected between REF IN (Pin 10) and ground. T his has the effect of improving the $S /(N+D)$ ratio through filtering possible broad-band noise contributions from the voltage reference.

## BOARD LAYOUT

Designing with high resolution data converters requires careful attention to board layout. T race impedance is a significant issue. At the 12 -bit level, a 5 mA current through a $0.5 \Omega$ trace will develop a voltage drop of 2.5 mV , which is 1 LSB for a 10 V full-scale range. In addition to ground drops, inductive and capacitive coupling need to be considered, especially when high accuracy analog signals share the same board with digital signals. Finally, power supplies should be decoupled in order to filter out ac noise.
The AD 1674 has a wide bandwidth sampling front end. This means that the AD 1674 will "see" high frequency noise at the input, which nonsampling (or limited-bandwidth sampling) ADC s would ignore. Therefore, it's important to make an effort to eliminate such high frequency noise through decoupling or by using an anti-aliasing filter at the analog input of the AD 1674.
Analog and digital signals should not share a common path. Each signal should have an appropriate analog or digital return routed close to it. U sing this approach, signal loops enclose a small area, minimizing the inductive coupling of noise. Wide PC tracks, large gauge wire, and ground planes are highly recommended to provide low impedance signal paths. Separate analog and digital ground planes are also desirable, with a single interconnection point to minimize ground loops. Analog signals should be routed as far as possible from digital signals and should cross them (if necessary) only at right angles.
The AD 1674 incorporates several features to help the user's layout. Analog pins are adjacent to help isolate analog from digital signals. Ground currents have been minimized by careful circuit architecture. Current through AGND is 2.2 mA , with little code-dependent variation. The current through DGND is dominated by the return current for D B11-D B0.

## SUPPLY DECOUPLING

The AD 1674 power supplies should be well filtered, well regulated, and free from high frequency noise. Switching power supplies are not recommended due to their tendency to generate spikes which can induce noise in the analog system.
D ecoupling capacitors should be used in very close layout proximity between all power supply pins and ground. A $10 \mu \mathrm{~F}$ tantalum capacitor in parallel with a $0.1 \mu \mathrm{~F}$ disc ceramic capacitor provides adequate decoupling over a wide range of frequencies.
An effort should be made to minimize the trace length between the capacitor leads and the respective converter power supply and common pins. The circuit layout should attempt to locate the AD 1674, associated analog input circuitry, and interconnections as far as possible from logic circuitry. A solid analog ground plane around the AD 1674 will isolate large switching ground currents. For these reasons, the use of wire-wrap circuit construction is not recommended; careful printed-circuit construction is preferred.

## GROUNDING

If a single AD 1674 is used with separate analog and digital ground planes, connect the analog ground plane to AGND and the digital ground plane to DGND keeping lead lengths as short as possible. T hen connect AGND and DGND together at the AD 1674. If multiple AD 1674s are used or the AD 1674 shares analog supplies with other components, connect the analog and digital returns together once at the power supplies rather than at each chip. This prevents large ground loops which inductively couple noise and allow digital currents to flow through the analog system.

## GENERAL MICROPROCESSOR INTERFACE CONSIDERATIONS

A typical A/D converter interface routine involves several operations. First, a write to the ADC address initiates a conversion. The processor must then wait for the conversion cycle to complete, since most ADCs take longer than one instruction cycle to complete a conversion. Valid data can, of course, only be read after the conversion is complete. The AD 1674 provides an output signal (ST S) which indicates when a conversion is in progress. This signal can be polled by the processor by reading it through an external three-state buffer (or other input port). The ST S signal can also be used to generate an interrupt upon completion of a conversion, if the system timing requirements are critical (bear in mind that the maximum conversion time of the AD 1674 is only 10 microseconds) and the processor has other tasks to perform during the ADC conversion cycle. Another possible time-out method is to assume that the ADC will take 10 microseconds to convert, and insert a sufficient number of "no-op" instructions to ensure that 10 microseconds of processor time is consumed.
Once it is established that the conversion is finished, the data can be read. In the case of an ADC of 8-bit resolution (or less), a single data read operation is sufficient. In the case of converters with more data bits than are available on the bus, a choice of data formats is required, and multiple read operations are needed. The AD 1674 includes internal logic to permit direct interface to 8 -bit or 16 -bit data buses, selected by the $12 / \overline{8}$ input. In 16-bit bus applications ( $12 / \overline{8} \mathrm{HIGH}$ ) the data lines (D B11 through DB0) may be connected to either the 12 most significant or 12 least significant hits of the data bus. The remaining four bits should be masked in software. The interface to an 8 -bit data bus ( $12 / \overline{8}$ LOW) contains the 8 M SBs (D B11 through D B4). The odd address ( $\mathrm{A}_{0} \mathrm{HIGH}$ ) contains the 4 LSBs (D B3 through $D B 0$ ) in the upper half of the byte, followed by four trailing zeroes, thus eliminating bit masking instructions.

| D7 D0 |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| XXXO (EVEN ADDR): | $\begin{aligned} & \hline \text { DB11 } \\ & \text { (MSB) } \end{aligned}$ | DB10 | DB9 | DB8 | DB7 | DB6 | DB5 | DB4 |
| xxxo (EVEN ADDR): | DB3 | DB2 | DB1 | $\begin{array}{\|c\|} \hline \text { DBO } \\ \text { (LSB) } \end{array}$ | 0 | 0 | 0 | 0 |

PACKAGE INFORMATION
Dimensions shown in inches and ( mm ).

## 28-Pin Ceramic DIP Package (D-28)



## 28-Lead Plastic DIP Package ( $\mathrm{N}-28$ )



28-Lead Wide-Body SO Package (R-28)



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[^1]:    NOTES
    ${ }^{1}$ For details on grade and package offerings screened in accordance with M IL-ST D-883, refer to the Analog D evices M ilitary Products D atabook or current AD 1674/883B data sheet. SM D is also available.
    ${ }^{2} \mathrm{~N}=$ Plastic DIP; $\mathrm{D}=\mathrm{H}$ ermetic C eramic DIP; R = Plastic SOIC.

